

Description

The VST25N160 uses **Super Trench** technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{\text{DS(ON)}}$ and Q_g . This device is ideal for high-frequency switching and synchronous rectification.

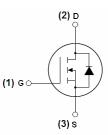
General Features

- $V_{DS} = 250V, I_{D} = 80A$ $R_{DS(ON)} < 18.5 m\Omega @ V_{GS} = 10V$
- Excellent gate charge x R_{DS(on)} product
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating
- 100% UIS tested

Application

- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification





Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VST25N160-TC	VST25N160	TO-220C	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	250	V	
Gate-Source Voltage	Vgs	±20	V	
Drain Current-Continuous	I _D	80	А	
Drain Current-Continuous(T _C =100°C)	I _D (100℃)	56.6	Α	
Pulsed Drain Current	I _{DM}	320	Α	
Maximum Power Dissipation	P _D	300	W	
Derating factor		2	W/℃	
Single pulse avalanche energy (Note 5)	E _{AS}	1200	mJ	
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}$	



Shenzhen VSEEI Semiconductor Co., Ltd

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 2)	Rejc	0.5	°C/W
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Electrical Characteristics (T_C=25 ℃ unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	250		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =250V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.5		4.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =40A	-	16	18.5	mΩ
Forward Transconductance	g FS	V _{DS} =10V,I _D =40A	70	-	-	S
Dynamic Characteristics (Note4)			•			•
Input Capacitance	C _{lss}	V _{DS} =125V,V _{GS} =0V,	-	5400	-	PF
Output Capacitance	C _{oss}		-	329	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	12	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}	V_{DD} =125V, I_{D} =40A V_{GS} =10V, R_{G} =4.7 Ω	-	18	-	nS
Turn-on Rise Time	t _r		-	26	-	nS
Turn-Off Delay Time	t _{d(off)}		-	41	-	nS
Turn-Off Fall Time	t _f		-	11	-	nS
Total Gate Charge	Qg	\/ -405\/ -404	-	76.7		nC
Gate-Source Charge	Q _{gs}	V _{DS} =125V,I _D =40A,	-	22.7		nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	20		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =80A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	80	Α
Reverse Recovery Time	t _{rr}	$T_J = 25^{\circ}C, I_F = 40$	-	140		nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	600		nC

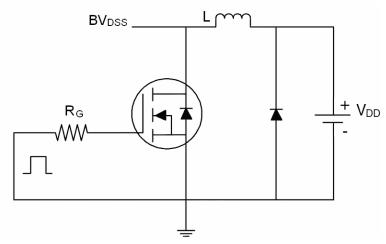
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t \leq 10 sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition : Tj=25 $^{\circ}\text{C}$,V_DD=50V,V_G=10V,L=0.5mH,Rg=25 Ω

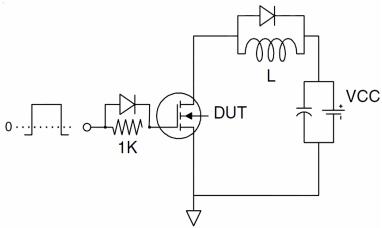


Test Circuit

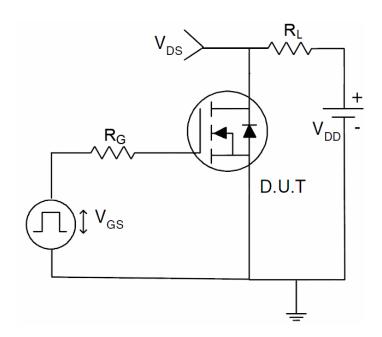
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit







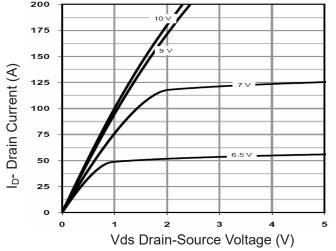


Figure 1 Output Characteristics

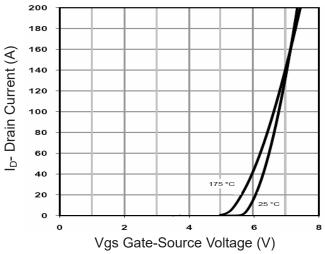


Figure 2 Transfer Characteristics

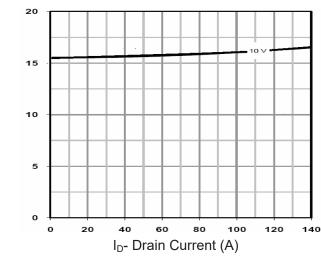


Figure 3 Rdson-Drain Current

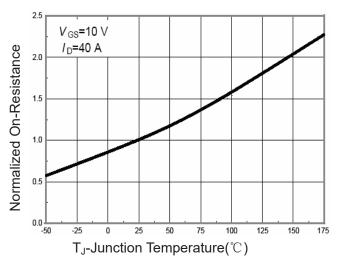


Figure 4 Rdson-JunctionTemperature

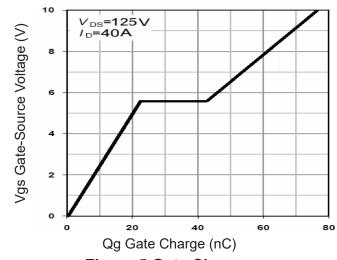


Figure 5 Gate Charge

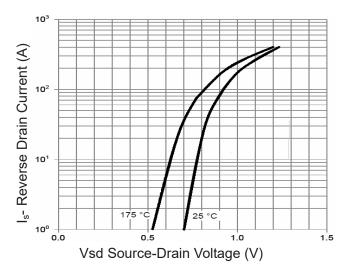


Figure 6 Source- Drain Diode Forward



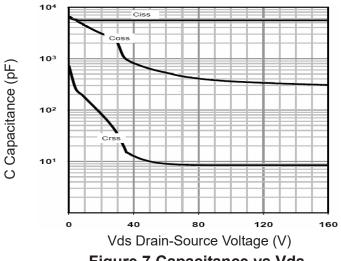


Figure 7 Capacitance vs Vds

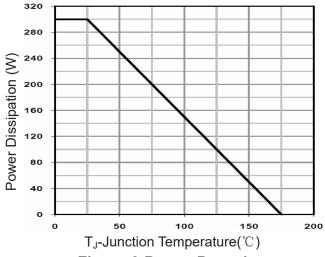


Figure 9 Power De-rating

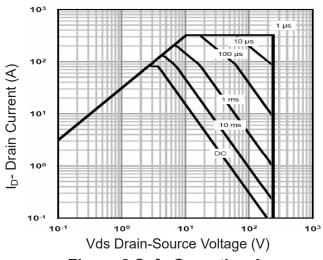


Figure 8 Safe Operation Area

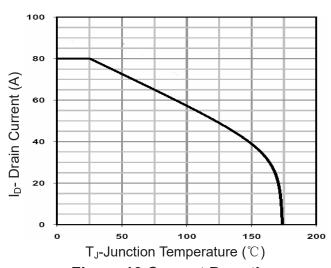
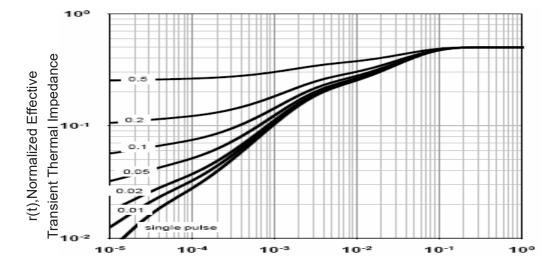


Figure 10 Current De-rating



Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance